

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/073,599	DAIGO ET AL.	
Examiner	Art Unit	
LUONG T. NGUYEN	2622	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
725/105; 348/231.99,231.3,231.6, 207.1,207.99,552 (text search only, see search history printout)	3/4/2006	LN
EAST (USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB) see search history printout	3/4/2006	LN
updated EAST, using previously cited references	3/30/2007	LN
updated EAST, using previously cited references	11/7/2007	LN
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